

WL15 Series

Linear IC Test System

Automated Test Equipment

Overview

The WL15 is a compact LSI test system designed for device characterization and mass-production test of linear ICs. It supports various modules used for DC parametric measurement, waveform analysis, time measurement, audio/video band measurements.

A real time operating system is used for the control of test sequence, and Microsoft Windows is used as operator interface. The system uses a Shibasoku original test programming language called "Tester-C", which is based on the familiar standard C programming language. The WL15 LSI Test System supports a maximum of 4 devices in parallel with individual DGS (Device Sense Ground) for greater accuracy.



Features

- High parallel test capability
 - Parallel test of 1, 2, or 4 devices
 - 4 DGS (independent device GND)
 - Ping-pong test mode for interface with two Handler Stations
- Reliable and accurate
 - Basic DC voltage accuracy: +/-0.05%
 - Test modules isolated from power supply
- Dual high speed CPUs with Windows GUI
 - C-language based system software
 - Powerful debug tool options
- Small foot print, flexible configurations
 - 15 module slots available for application modules

Specifications

- Per-pin source
 - Max. 32 pins
 - +/-32 V, +/-32 mA x 8 ch / Module
- DC voltmeter
 - 2 inputs
 - +/-32 V max. (Single)
 - +/-64 V max. (Differential)
- V/I source options
 - +/-50 V, +/-250 mA
 - +/-128 V, +/-250 mA (+/-40 V, +/-2 A)
- Time measurement
 - 10 nsec to 6 sec
 - Resolution 100 psec
 - Accuracy +/- (10ppm+10 ns)
- Parallel test capability
 - 1 / 2 / 4 DUTs

Target Applications

Voltage Regulators, Operational Amplifiers, Comparators, MOS-FET, Audio Amps, IPD

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